150

10.5

37

٧

 $\mathsf{m}\Omega$ 

**Product Summary** 

 $V_{\rm DS}$ 

 $I_{\mathsf{D}}$ 

 $R_{\mathrm{DS(on),max}}$ 



# **Opti**MOS<sup>™</sup>3 Power-Transistor

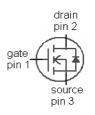
### **Features**

- N-channel, normal level
- Excellent gate charge x  $R_{\,\mathrm{DS(on)}}$  product (FOM)
- Very low on-resistance R<sub>DS(on)</sub>
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC1) for target application
- Halogen-free according to IEC61249-2-21





Туре	IPA105N15N3 G
	<b>D</b>
Package	PG-TO220-FP
Marking	105N15N



# **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C <sup>2)</sup>	37	А
		T <sub>C</sub> =100 °C	27	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	148	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{\rm D}$ =37 A, $R_{\rm GS}$ =25 $\Omega$	740	mJ
Gate source voltage	$V_{GS}$		±20	V
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	40.5	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

<sup>1)</sup>J-STD20 and JESD22

<sup>&</sup>lt;sup>2)</sup> See figure 3

s



Transconductance

Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	$R_{\mathrm{thJC}}$		-	-	3.7	K/W
<b>Electrical characteristics</b> , at $T_j$ =25	°C, unless	otherwise specified				
Static characteristics						
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	150	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 160  \mu {\rm A}$	2	3	4	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS}$ =120 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	-	0.1	1	μА
		V <sub>DS</sub> =120 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V		1	100	nA
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	V <sub>GS</sub> =10 V, I <sub>D</sub> =37 A	-	9.1	10.5	mΩ
		V <sub>GS</sub> =8 V, I <sub>D</sub> =18 A	-	9.5	11.1	
Gate resistance	$R_{G}$		-	2.4	-	Ω

1<sub>D</sub>=37 A

 $g_{\mathsf{fs}}$ 

 $|V_{\rm DS}| > 2|I_{\rm D}|R_{\rm DS(on)max}$ 

33

65

 $<sup>^{3)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^2$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol	Symbol Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	3230	4300	рF
Output capacitance	Coss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =75 V, f=1 MHz	-	378	503	
Reverse transfer capacitance	C <sub>rss</sub>		-	7	-	
Turn-on delay time	$t_{d(on)}$		1	17	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =75 V, V <sub>GS</sub> =10 V,	1	20	-	
Turn-off delay time	$t_{d(off)}$	$I_D$ =37 A, $R_G$ =1.6 Ω	-	35	1	
Fall time	t <sub>f</sub>		-	9	-	7
Gate Charge Characteristics <sup>4)</sup>				1	T	
Gate to source charge	Q <sub>gs</sub>		-	17	-	nC
Gate to drain charge	Q <sub>gd</sub>	V <sub>DD</sub> =75 V, I <sub>D</sub> =37 A,	-	7	-	1
Switching charge	Q <sub>sw</sub>	$V_{\rm DD}$ -75 V, $V_{\rm D}$ -37 A, $V_{\rm GS}$ =0 to 10 V	-	13	-	_
Gate charge total	Q <sub>g</sub>		-	41	55	
Gate plateau voltage	V <sub>plateau</sub>		-	5.1	-	٧
Output charge	Q <sub>oss</sub>	$V_{\rm DD}$ =75 V, $V_{\rm GS}$ =0 V	ı	106	141	nC
Reverse Diode						
Diode continous forward current	Is	- T <sub>C</sub> =25 °C	-	-	37	А
Diode pulse current	I <sub>S,pulse</sub>	7 6-23 0	1	-	148	
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =37 A, T <sub>j</sub> =25 °C	-	0.9	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =50 V, I <sub>F</sub> =37 A,	-	115	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100 A/µs	-	380	-	nC

<sup>&</sup>lt;sup>4)</sup> See figure 16 for gate charge parameter definition

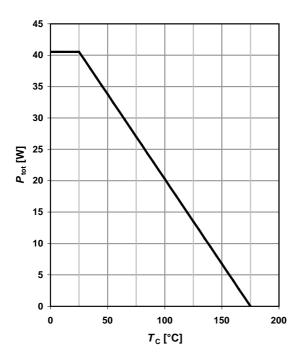


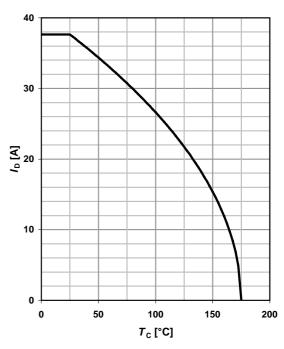
### 1 Power dissipation

# $P_{\text{tot}}$ =f( $T_{\text{C}}$ )

# 2 Drain current

$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$





# 3 Safe operating area

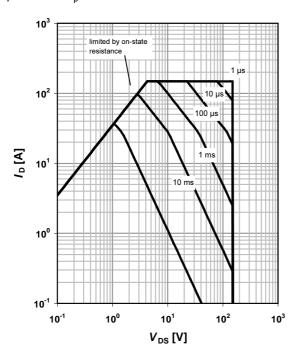
$$I_D$$
=f( $V_{DS}$ );  $T_C$ =25 °C;  $D$ =0

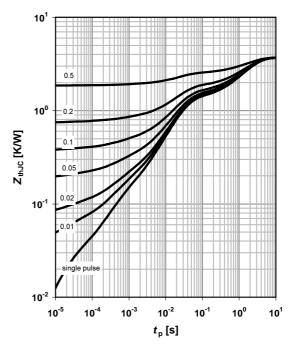
parameter:  $t_p$ 

### 4 Max. transient thermal impedance

$$Z_{\rm thJC}$$
=f( $t_{\rm p}$ )

parameter:  $D=t_p/T$ 



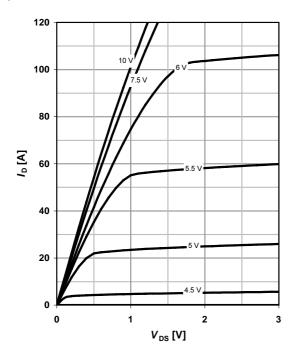




### 5 Typ. output characteristics

 $I_D$ =f( $V_{DS}$ );  $T_j$ =25 °C

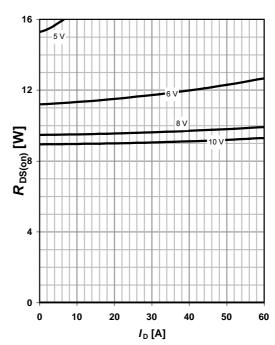
parameter:  $V_{\rm GS}$ 



### 6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

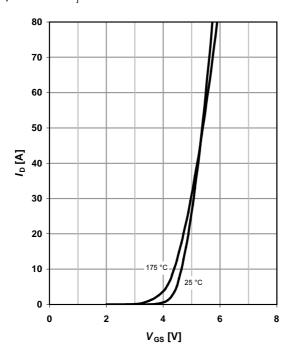
parameter:  $V_{\rm GS}$ 



# 7 Typ. transfer characteristics

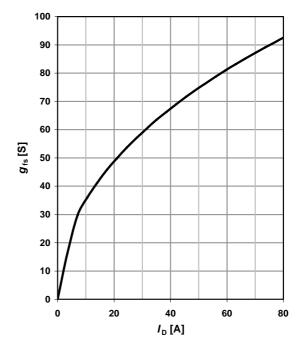
 $I_{D}$ =f( $V_{GS}$ );  $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$ 

parameter:  $T_{\rm j}$ 



# 8 Typ. forward transconductance

$$g_{fs}$$
=f( $I_D$ );  $T_j$ =25 °C





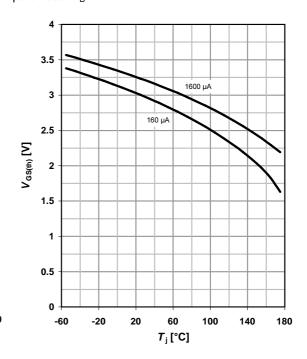
### 9 Drain-source on-state resistance

 $R_{DS(on)}$ =f( $T_j$ );  $I_D$ =37 A;  $V_{GS}$ =10 V

# 25 20 20 15 10 5 0 -60 -20 20 60 100 140 180 T<sub>j</sub> [°C]

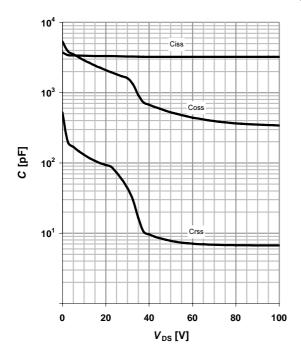
### 10 Typ. gate threshold voltage

 $V_{\rm GS(th)}$ =f( $T_{\rm j}$ );  $V_{\rm GS}$ = $V_{\rm DS}$ parameter:  $I_{\rm D}$ 



### 11 Typ. capacitances

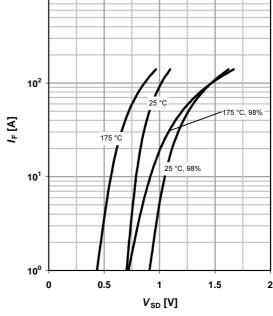
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 



### 12 Forward characteristics of reverse diode

 $I_{\text{F}} = f(V_{\text{SD}})$ parameter:  $T_{\text{j}}$ 

10<sup>3</sup>

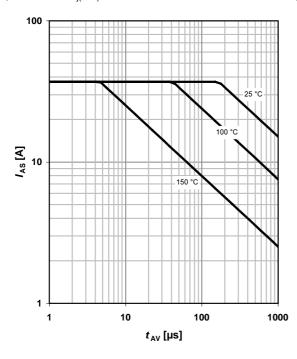




### 13 Avalanche characteristics

 $I_{\mathsf{AS}}$ =f( $t_{\mathsf{AV}}$ );  $R_{\mathsf{GS}}$ =25  $\Omega$ 

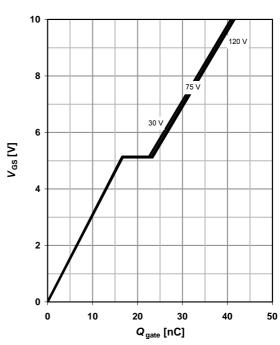
parameter:  $T_{j(start)}$ 



# 14 Typ. gate charge

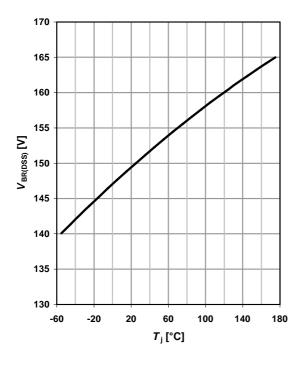
 $V_{\rm GS}$ =f(Q<sub>gate</sub>);  $I_{\rm D}$ =37 A pulsed

parameter: V<sub>DD</sub>

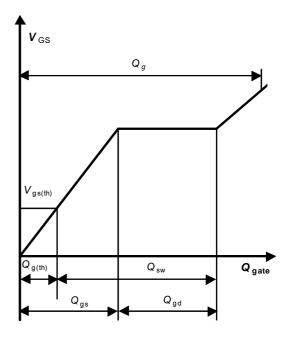


### 15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f( $T_j$ );  $I_D$ =1 mA

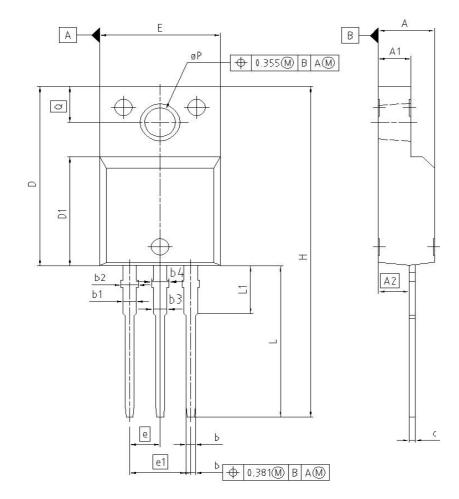


### 16 Gate charge waveforms





### PG-TO220-FP



DIM	MILLIN	MILLIMETERS		HES
DIM	MIN	MAX	MIN	MAX
A	4.55	4.85	0.179	0.191
A1	2.55	2.85	0.100	0.112
A2	2.42	2.72	0.095	0.107
b	0.65	0.85	0.026	0.033
b1	0.95	1.33	0.037	0.052
b2	0.95	1.51	0.037	0.059
b3	0.65	1.33	0.026	0.052
b4	0.65	1.51	0.026	0.059
c	0.40	0.63	0.016	0.025
D	15.85	16.15	0.624	0.636
D1	9.53	9.83	0.375	0.387
E	10.35	10.65	0.407	0.419
е	2.	54	0.1	00
e1	5.	08	0.2	200
N		3		3
Н	29.45	29.75	1.159	1.171
L	13.45	13.75	0.530	0.541
L1	3.15	3.45	0.124	0.136
pΡ	2.95	3.20	0.116	0.126
0	3.15	3.50	0.124	0.138

REFERENCE/				
SCALE	0			
0 2.5 Luuuuuluu	2.5 5mm			
EUROPEAN PR	OJECTION			
	<del>-</del> ф-			
I <b>SSUE D</b> . 08-01-2	35 S S S S S S S S S S S S S S S S S S S			
FILE TO220	i			



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